Appl. No.   : 09/839,013
Filed   : April 21, 2001

IN THE ABSTRACT:

A semiconductor test system is capable of time critical sequence generation using a general purpose operating system. The semiconductor test system includes a tester hardware for providing power sources and test patterns to a device under test, a host computer operated by a general purpose operating system, a configuration software for computing configuration data and timing data based on a test program, a device driver for providing a power trigger and a signal trigger to the tester hardware, and a hardware timer for producing an interrupt signal. The device driver causes to start the test pattern and to deactivate the power sources upon receiving the interrupt signal <u>generated by the hardware timer and transferred from the host computer</u>.